



透射电镜（TEM）可对试样在纳米和埃的层级给出相应的物质结构信息，不仅能够直观地观测样品形貌，更能细致分析样品的精细结构，可与地质、化工、高分子科学、生命科学、医药学、材料、半导体等学科实现共享。JEOL Jem-2100plus: 加速电压 200kv, 点分辨率 0.194nm, 线分辨率 0.14nm, 可完成超高分辨成像、明暗场像、电子衍射、微结构分析、形貌分析、晶体结构确定等。

Transmission electron microscopy (TEM) can give the corresponding material structure information at the level of nanometer and angstrom. It can not only visually observe the morphology of samples, but also analyze the fine structure of samples in detail, and can be related to geology, chemical engineering, polymer science, life science, medicine, materials, semiconductor and other disciplines.

JEOL Jem-2100plus: Acceleration voltage of 200 kv, point resolution of 0.194 nm, line resolution of 0.14 nm, which can complete ultra-high resolution imaging, light and dark field imaging, electron diffraction, micro-structure analysis, morphology analysis, crystal structure determination, etc.